



EV371300620

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 10/757,253
Confirmation No. 4387
Filing Date January 13, 2004
Inventor..... Denise M. Eppich et al.
Assignee..... Micron Technology, Inc.
Group Art Unit..... 2823
Examiner Hsien-Ming Lee
Attorney's Docket No. MI22-2467
Customer No. 021567
Title: Methods of Forming Transistor Devices and Capacitor Constructions

INFORMATION DISCLOSURE STATEMENT to accompany RCE

References -- See Attached Form PTO-1449

The attached Form PTO-1449 is submitted in compliance with 37 CFR §1.56. Pursuant to FEDERAL REGISTER, Vol. 69, No. 182, pg. 56542 (September 21, 2004), no copies of any cited U.S. patents or U.S. published applications are included herewith.

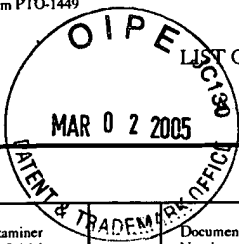
No admission is made regarding whether the listed references are prior art.

Dated: 3/4/05

Respectfully submitted,

By: [Signature]

David G. Latwesen, Ph.D.
Wells St. John P.S.
Reg. No. 38,533

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-2467		SERIAL NO. 10757,253	
				LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)			
				APPLICANT Denise M. Eppich et al.			
				FILING DATE Jan. 13, 2004 [RCE filed herewith]		GROUP 2823	
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA	5,705,428	01/98	Liu et al.			
	AB	6,306,743 B1	10/01	Lee			
	AC	6,436,749 B1	08/02	Tonti et al.			
	AD	6,573,160 B2	06/03	Taylor Jr. et al.			
	AE	6,255,698 B1	07/01	Gardner et al.			
	AF	6,693,333 B1	02/04	Yu			
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AM						
	AN						
	AO						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AP						
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U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	2003/ 0129793 A1	07/03	Chau et al.			
	AB	2004/ 0065903 A1	04/04	Zheng et al.			
	AC	2004/ 0038538 A1	02/04	Ho et al.			
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AJ						
	AK						
	AL						
	AM						
	AN						
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